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Session A: Advances in Measurements I

On downconverter noise characterization for LO waveform sensitivities...1
Jon Martens
Anritsu Company

An Adaptable Time Domain Gating Implementation with Enhanced Edge Treatment for Facilitating Vector Frequency Domain Data Analyses...5
Zhong Chen
ETS-Lindgren

Session B: On-Wafer measurements and Calibration

Precision Printed Circuit Board Probing Into W-Band...11
Hugo Morales[1], Chris DeMartino[1], Dave Barry[1], Larry Dunleavy[1,2]
[1] Modelithics Inc., Boulder, [2]University of South Florida

Error-Box Calibration of Three-Sampler VNAs...15
Ziad Hatab, Michael Ernst Gadringer, Wolfgang Bosch
Graz University of Technology

Session C: Advances in Measurements II

Efficient Calibration of RFSoC Full Digital Receiving Beamformer...19
Peizhuo Yang, Jiahao Wang, Koen Mouthaan
National University of Singapore

Double-pulse load-pull for trapping Characterization of GaN Transistors...23
Gustavo Avolio[1], Martino Lorenzini[2], Nikolai Balovnev[1], Mauro Marchetti[1]
[1]Maury Microwave, [2]Gallium Semiconductor

Session D: On-Wafer and EVM Measurements

Discrimination between Noise and Distortion in EVM Measurements...27
Jacques Sombrin[1], Benjamin Ros[2], Aurélien Chaumet[2]
[1]TéSA Laboratory, [2]CNES

Identifying Quasi-Identical Power Amplifiers through EVM and NMSE Measurements of Output Data using Digital Post Distortion...31
Nicholas Ellis[1], Patrick Roblin[1], James Gaudreau[2], Joel T. Johnson[2], Justin Kuric[2], Christopher Ball[2],Richard Ridgway[2]
[1]Non-Linear RF Lab, Ohio State University, [2]ElectroScience Laboratory, Ohio State University

Session E: Generalized Network Analysis and Load-Pull

Benchmarking a High Electron Mobility Transistor Using an Active Load-Pull System at 120 GHz -170 GHz...34
Jing Wang, Afesomeh Ofiare, Hui-Hua Cheng, Edward Wasige, Chong Li
University of Glasgow

Discussion on System-Level Wideband Active Load-Pull Linearity Measurements: How to Reach Broadband Design Techniques?...38

Ricardo Figueiredo[1], Sanket Chaudhary[3], Marc Vanden Bossche[4], Mohadig Rousstia[5], Mauro Marchetti[3], Nuno Borges Carvalho[1,2]

[1]Instituto de Telecomunicacoes, [2]Universidade de Aveiro, [3]Anteverta-mw B.V, [4]National Instruments, [5]Ampleon